	Application/Control No.	Applicant(s)/Patent Under Reexamination
Issue Classification	09664855	ENOKI ET AL.
	Examiner	Art Unit
	Nguyen, Huy D	2617

CLASS 455 CROSS CLASS SUBCL 455 572 343.1					INTERNA	TIONAL C	INTERNATIONAL CLASSIFICATION	-
C STZ S72		SUBCLASS			CLAIMED		NON-CI	NON-CLAIMED
C 1.1.4.5.5 57.2	574		Ξ	4	В	1 / 38		
572 572	CROSS REFERENCE(S)	(s)						
572	SUBCLASS (ONE SUBCLASS PER	LASS PER BLOCK)		_				
	343.2							
				-				
A Particular and the second and the								
				_				
				-				
					1			
ra/26/1	5/07	1	_	_			Total Claims Allowed:	s Allowed:
:xaminer)		JOSEPH FEILD	_ \					
Specifica or region	σ,	UPERVISÕRY PRIENTEX		1	7,5		O.G. Print Claim(s)	O.G. Print Figure
egal Instruments Examiner) (Date)		(Primary Examiner)		) Date	/(Date)/0>		-	1A

U.S. Patent and Trademark Office